SPECIFICATIONS

General

Maximum Analog Test Points	3200 or Maximum Digital Test Points: 1600
IBM® Compatible PC	
Operation System	Microsoft® Windows XP/Windows 7
Power Requirement	90 - 130 V/180 - 240 V Auto-Switch, Single phase, 50/60 Hz,1 kVA.
Air Requirement	Dry Air 4 - 8 kg/cm², Air Consumption: 4 Liter/cycle
Fixture Type	Press Type
Testable PCB Size Standard Option	 (W) 420 mm x (D) 300 mm x (H) 100 mm (W) 500 mm x (D) 350 mm x (H) 130 mm Large size PCB can be specially made

Analog Hardware

Measurement Switching Matrix	6-wire measurement
Programmable Frequency	100 Hz, 1 kHz, 10 kHz, 100 kHz, 1 MHz
Programmable DC Voltage Source	0 - ±10 V, Resolution: 6.1 mV
Programmable DC Current Source	0 - 100 mA, Resolution: 0.2 mA
Programmable AC Voltage Source	0 - 12 Vpp, Resolution: 6.1mV
Programmable High Voltage DC Source	43 V max, 43 mA max
Component Measurement Capability	
Resistance	0.1 ohm - 40M ohm
Capacitance	10 pF - 40 mF
Inductance	10 µH - 60 H
Analog Measurement	
AC Voltmeter	0 - 100 V
DC Voltmeter	0 - ±100 V, Resolution: 2.5 mV - 50 mV
DC Ampmeter	1 µA - 100 mA Resolution: 30 nA - 30 µA

Optional Hardware

Analog Test	
TestJet Technology	Vectorless Open Circuit Detection
Arbitrary Waveform Generator (AWG)	Frequency Range 0 - 100 KHz, Resolution: 0.15 Hz
Digital Test	
Non-Multiplexing 1:1 Per Pin Architecture	
Pin Drivers	Programmable Levels 0.5 V to 3.8 V
Pin Receivers	Programmable Levels 0 V to 5 V
Pull-up/Pull-down Resistor	4.7 K
DUT Power Supplies(Voltage/Max current)	5V/3A, 3.3V/3A, 12V/3A, 18V/3A, -12V/1A, 24V/3A
Programmable DUT Power Supplies (Max Voltage/Max current)	25V/8A, 75V/2.5A
On-board Programming of Flash & EEPROM Memories	
MAC Address Programming	Supports MAC address programming with MAC address being supplied from server
Boundary Scan	Include B-scan Chain Test, B-scan Cluster Test, B-Scan Virtual Nails Test and IEEE1149.6 Test Facilities to meet demands of multiple tests
ToggleScan™ Test	Advanced test technology combining with BScan test function and Vectorless test functions to detect the pin open and short defect
Tree Test Facilities with BGA Test	Pattern Generator for detection of pin opens for BGA/VLSI Chips

Dimensions/Weight

Dimensions	(W) 1000 mm x (D) 900 mm x (H) 1680 - 1770 mm
Weight	200 kg

Powerful Software Environment

- Microsoft® Windows operating system software   User friendly interface
- Automatic Test Program Generator
- Automatic protection of specific points during debug
- Auto-learning and test program generation for opens/shorts test, clamping diode test and TestJet test
- Auto debug of passive components
- Built-in self-diagnostic function
- Board view instantly displays failed devices and pins

Specifications are subject to change without notice. Content may not be used as acceptance criteria.
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C-5001E-EN-1507

TR5001E SERIES

IN-CIRCUIT TESTER

TR5001E FEATURES

The Most Cost-Effective Test Strategy

Non-Multiplexing Pin Design, Driver/Receiver to Pin Ratio 1:1 .

- Optimized Nail Placement with 1:1 Ratio Flexibility
- ECNs only require moving few existing wires compared with 2:8/2:9 driver/receiver per pin
- 1:1 Driver/Receiver per pin provide for the fastest test program development and debugging

The most flexible ICT+FCT solution in the market. TR5001E can integrate with external instruments for functional tests such as: PXI, Labview, ...etc.

Analog Test

R, L, C Measurement
- 6-Wire Measurement
- Auto-Guarding Feature
- AC Phase Measurement

TRI Enhanced TestJet
Detects open connections on ICs, connectors and other SMT devices.

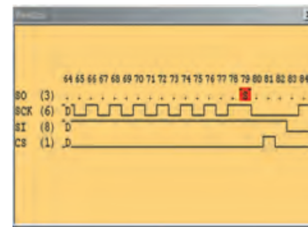
Transistor/Diode Measurement

TRI Enhanced TestJet

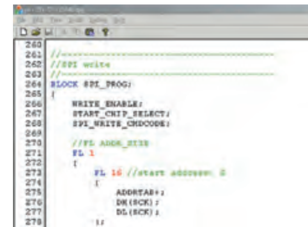
TR5001E

Digital Test

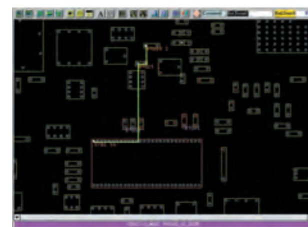
- Full digital in-circuit test (ICT)
- Friendly UI
- On-Board Programming
- Boundary Scan
  Auto-Generation of test programs



Waveform Display



Color Syntax
Program Editor



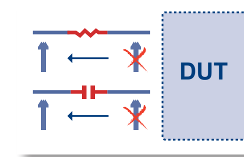
Board View with Trace
Display Capability

Flash Programming

Limited Access Solution

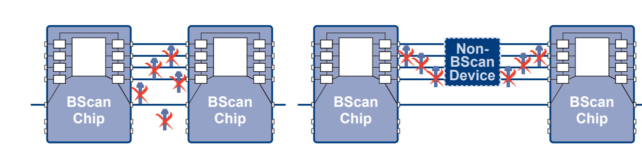
Drive Through Test

Greatly reduces test probes for passive analog components connected in series with JTAG and BScan capable devices and connectors.



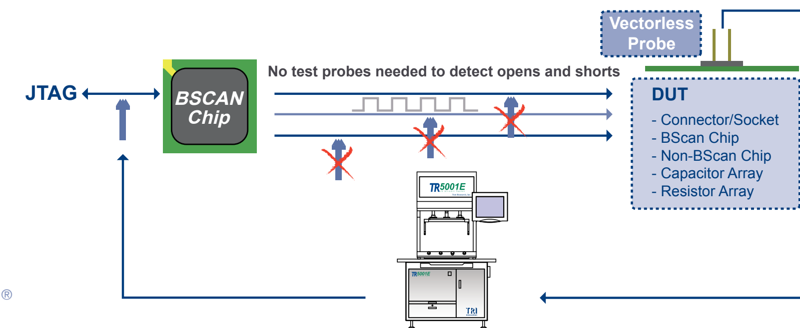
Boundary Scan Test

Virtual nails tests for RAM, ROM, TTL and TREE devices, and IEEE1149.6 Test.



TRI ToggleScan® Test

A powerful vectorless test technology that significantly reduces number of test probes, ToggleScan utilizes BScan and vectorless probes to test non-Bscan devices.



VregTest®

Test PWM circuits without test probes.

TRI CPU Socket Test

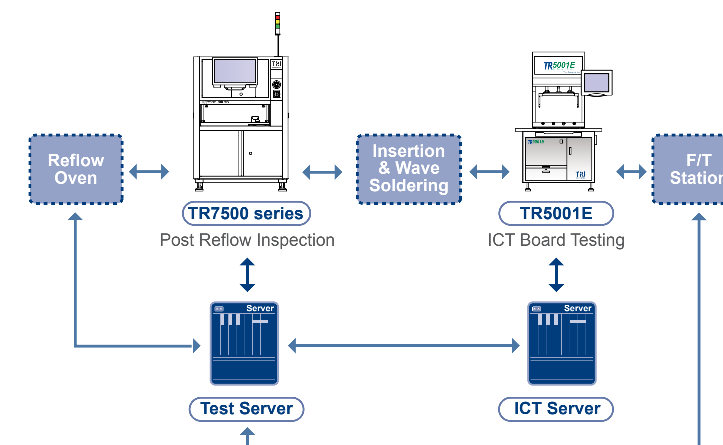
Quickly tests LGA CPU sockets using a specialized vectorless probe in connection with an onboard BSCAN device.

Dual-Stage Press Unit

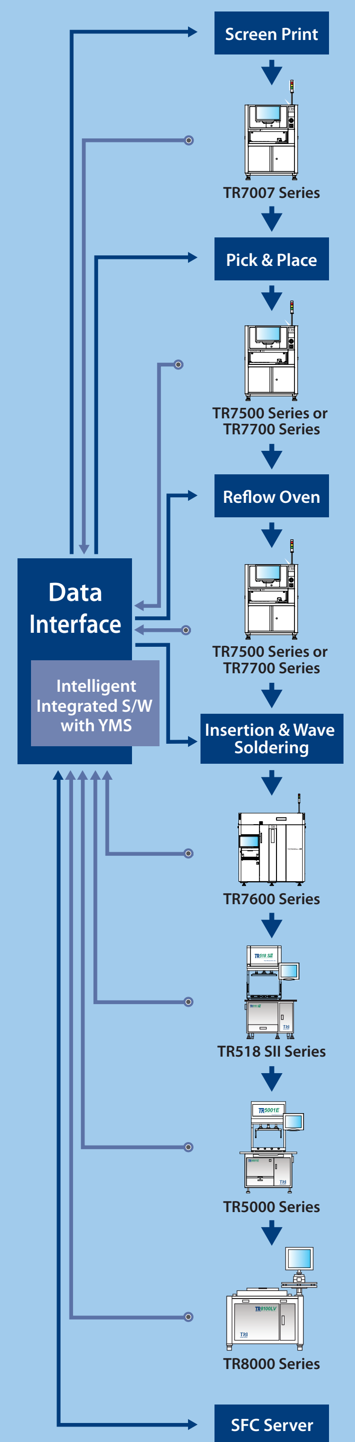
Reduces fixture costs with built-in dual-stage press unit for ICT Functional Test.

Shop Floor System Support

TR5001E can integrate with many shop floor systems to help centralize production line management and improve production quality using gathered testing data.



Yield Management System*



- Inspection results and data integration
- Real time SPC and production yield management
- Quality reports and closed loop tracking
- Support defect component analysis and improvements
- Knowledge Management (KM)
- Productivity and Quality Management

* Optional